

Search Notes

Application/Control No.

10/528,529

Examiner

Nam Huynh

Applicant(s)/Patent under
Reexamination

VANDER VEEN ET AL.

Art Unit

2617

SEARCHED

Class	Subclass	Date	Examiner
379	142.06	4/17/2006	NTH
	142.09		
	142.01		
	142.04		
	142.17		
455	415	4/17/2006	NTH

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
See EAST search notes.	4/17/2006	NTH